

..... **DYNAMIC HTRB SYSTEMS for diodes and transistors** .....

This dynamic HTRB system is designed for testing of ruggedness of devices to withstand puls voltages with high du/dt and has following parameters :



**Test capacity:** 4 x 80 DUTs

**Test chambers :** 4

**Temperature range :** 50°C to 200°C per chamber

**Test boards per chamber :** 4

**Possible voltage range :** 0V to 1500V

**Rise time :** max. 50ns to 1500V, possibility of lower du/dt

**Pulse frequency :** 100Hz to 100kHz

**Duty cycle :** 1% to 99%

**Operating system :** MS Windows XP

**Handling :** Comfortable graphic platform

**Alarms :** Programmable, light or sound

**System controls :** Continous for voltages and temperatures of chambers

**DUT controls :** Continous for bias voltages and leakage currents with alarm and disconnection of test board by values over programmable limits